

LMN6184DF 60V N-Channel Enhancement Mode MOSFET

Features

- $R_{DS(ON)}=92m\Omega@V_{GS}=10V$
- $R_{DS(ON)}=100m\Omega@V_{GS}=4.5V$
- Improved dv/dt capability
- Fast switching
- 100% EAS guaranteed.

Product Description

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has

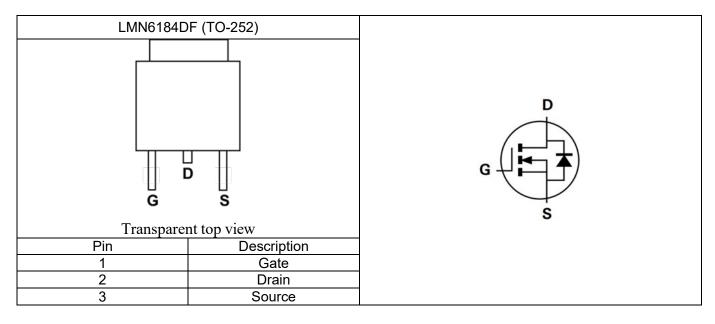
been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are well suited for high efficiency fast switching applications.

Applications

- Motor Drive
- Power Tools
- LED Lighting

Pin Configuration

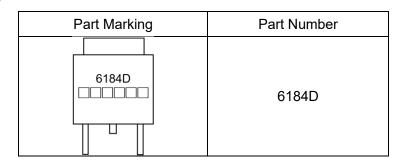




Ordering Information

Ordering Information						
Part Number	P/N	PKG code	Pb Free code	Package	Quantity	
LMN6184DF	LMN4184	D	F	TO-252	2500 PCS	

Marking Information



Absolute Maximum Ratings

(T_C=25°C Unless otherwise noted)

Symbol	Parameter	Parameter		Unit
V_{DSS}	Drain-Source Voltage	Drain-Source Voltage		V
V _{GSS}	Gate-Source Voltage	Gate-Source Voltage		V
	Continuous Drain Current ¹	T _C =25°C	10	
•		T _C =100°C	6	Δ.
l _D		T _A =25°C	3	A
		T _A =70°C	2	
I _{DM}	Pulsed Drain Current ²		20	A
I _{AS}	Single Pulse Avalanche Curr	Single Pulse Avalanche Current		А
E _{AS}	Single Pulse Avalanche Ene	Single Pulse Avalanche Energy ³		mJ
	Total Power Dissipation ⁴	T _C =25°C	20.8	
<u></u>		T _C =100°C	8.3	10/
P_{D}		T _A =25°C	2	W
		T _A =70°C	1.2	
TJ	Operating Junction Tempera	Operating Junction Temperature		°C
T_{STG}	Storage Temperature Range	Storage Temperature Range		°C
R _{θJC}	Thermal Resistance, Junctio	Thermal Resistance, Junction to Case ¹		°C /W
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient ¹		62	°C /W



Electrical Characteristics

(T_C=25°C Unless otherwise noted)

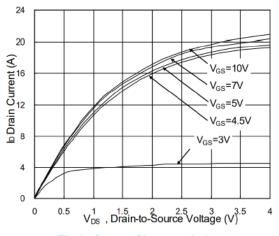
Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
	Static						
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} =0 V , I_D =250 u A	60			V	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{D}=250uA$	1		3	V	
I_{GSS}	Gate Leakage Current	V_{DS} =0V, V_{GS} =±20V			±100	nΑ	
I _{DSS}	Zero Gate Voltage Drain Current	V_{DS} =60V, V_{GS} =0V			1	uA	
R _{DS(on)}	Drain-Source On-Resistance ²	V_{GS} =10V, I_D =6A		85	92	mΩ	
1 (DS(on)		V_{GS} =4.5V, I_D =3A		90	100		
9 FS	Forward Transconductance	V_{DS} =10V, I_{D} =3A		3.6		S	
		Dynamic					
Q_g	Total Gate Charge	V _{DS} =48V, V _{GS} =4.5V,		4.9		nC	
Q_gs	Gate-Source Charge	$I_{D}=10A$		1.8			
Q_gd	Gate-Drain Charge	ID-TOA		2.2			
C _{iss}	Input Capacitance	\/ -15\/ \/ -0\/		511		pF	
Coss	Output Capacitance	V_{DS} =15V, V_{GS} =0V, f=1MHz		38			
C _{rss}	Reverse Transfer Capacitance	1-11/11/12		25			
t _{d(on)}	Turn-On Time ^{2,3}			6		ns	
t _r	Tum-On Time-,	V_{DD} =30V, I_{D} =3A,		9			
$t_{d(off)}$	Turn-Off Time ^{2,3}	V_{GS} =4.5V, R_{G} =3.3 Ω		18			
t _f	Turn-Oil Time ^{2,9}			5			
Diode characteristics							
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V, I _S =10A			1.4	V	
I _S	Continuous Source Current ¹	$V_G=V_D=0V$,			10	А	
ıs	Continuous Source Current	Force Current					
trr	Reverse Recovery Time	$I_S=3A$, $V_{GS}=0V$		19		nS	
Qrr	Reverse Recovery Charge	dI/dt=100A/μs		28		nC	

Note:

- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2. The data tested by pulsed, pulse width \leq 300us, duty cycle \leq 2%
- 3. The EAS data shows Max. rating. The test condition is VDD=25V, VGS=10V, L=0.1mH, IAS=11.2A
- 4. The power dissipation is limited by $150\,^{\circ}\mathrm{C}$ junction temperature
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



Typical Performance Characteristics



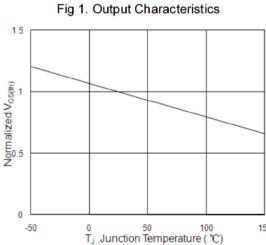


Fig. 3 Normalized Gate Threshold Voltage

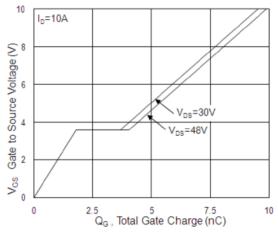


Fig. 5 Gate Charge Characteristics

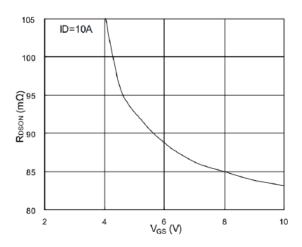


Fig. 2 On-Resistance vs. Gate Source

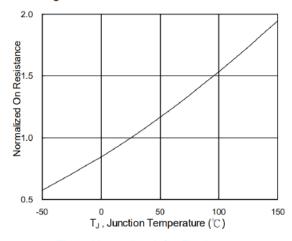


Fig. 4 Normalized On-Resistance

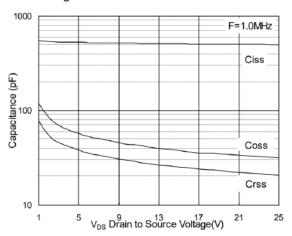


Fig. 6 Typical Capacitance



Typical Performance Characteristics

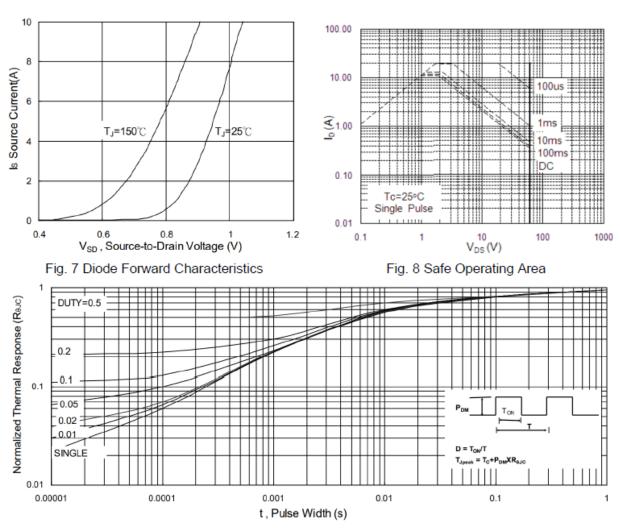


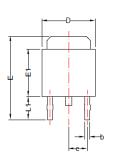
Fig. 9 Transient Thermal Impedance

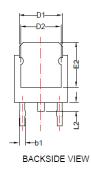


Package Dimension:

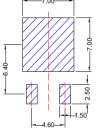
TO-252

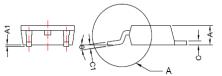
Package Dimension

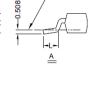




Recommended Land Pattern







	Dimensions				
Compleal	Millimeters		Inches		
Symbol	Min	Max	Min	Max	
Α	2.18	2.40	0.086	0.094	
A1	0.00	0.15	0.000	0.006	
b	0.50	0.90	0.020	0.035	
С	0.45	0.89	0.018	0.035	
c1	0.40	0.61	0.016	0.024	
D	6.35	6.80	0.250	0.268	
D1	4.95	5.50	0.195	0.217	
D2	3.81	-	0.150	-	
E	9.40	10.41	0.370	0.410	
E1	5.33	5.80	0.210	0.228	
E2	4.57	-	0.180	-	
е	2.286 BSC		0.090 BSC		
L	1.40	1.78	0.055	0.070	
L1	2.40	3.00	0.094	0.118	
θ	0°	8°	0°	8°	



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